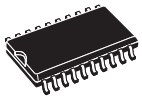
74LVQ273

OCTAL D-TYPE FLIP FLOP WITH CLEAR

- HIGH SPEED:
  f_{MAX} = 150 MHz (TYP.) at V_{CC} = 3.3 V
- COMPATIBLE WITH TTL OUTPUTS
- LOW POWER DISSIPATION:
  I_{CC} = 4 µA (MAX.) at T_A=25°C
- LOW NOISE:
  V_{OLP} = 0.4V (TYP.) at V_{CC} = 3.3V
- 75Ω TRANSMISSION LINE DRIVING CAPABILITY
- SYMMETRICAL OUTPUT IMPEDANCE:
  $|I_{OH}| = I_{OL}$ = 12mA (MIN) at V_{CC} = 3.0 V
- PCI BUS LEVELS GUARANTEED AT 24 mA
- BALANCED PROPAGATION DELAYS:
  $t_{PLH} \cong t_{PHL}$
- OPERATING VOLTAGE RANGE:
  V_{CC}(OPR) = 2V to 3.6V (1.2V Data Retention)
- PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 273
- IMPROVED LATCH-UP IMMUNITY



SOP

TSSOP

ORDER CODES

PACKAGE	TUBE	T & R
SOP	74LVQ273M	74LVQ273MTR
TSSOP		74LVQ273TTR

DESCRIPTION

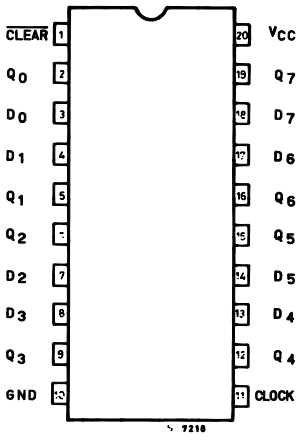
The 74LVQ273 is a low voltage CMOS OCTAL D-TYPE FLIP FLOP WITH CLEAR fabricated with sub-micron silicon gate and double-layer metal wiring C^2MOS technology. It is ideal for low power and low noise 3.3V applications.

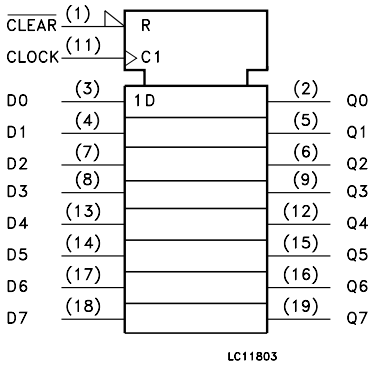
Information signals applied to D inputs are transferred to the Q outputs on the positive going edge of the CLOCK pulse.

When the CLEAR input is held low, the Q outputs are held low independently of the other inputs.

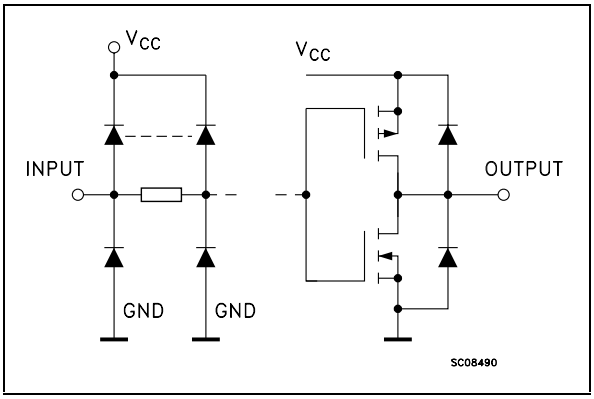
All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

PIN CONNECTION AND IEC LOGIC SYMBOLS





INPUT AND OUTPUT EQUIVALENT CIRCUIT



PIN DESCRIPTION

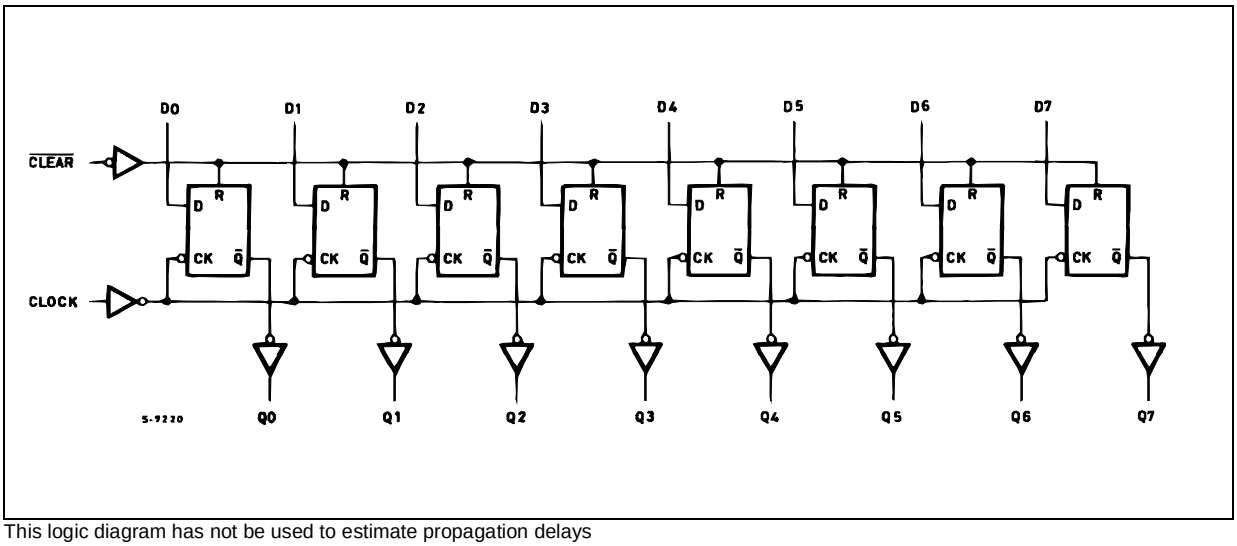
PIN No	SYMBOL	NAME AND FUNCTION
1	$\overline{CLEAR}$	Asynchronous Master Reset (Active LOW)
2, 5, 6, 9, 12, 15, 16,19	Q0 to Q7	Flip-Flop Outputs
3, 4, 7, 8, 13, 14, 17, 18	D0 to D7	Data Inputs
11	CLOCK	Clock Input (LOW-to-HIGH Edge Triggered)
10	GND	Ground (0V)
20	V_{CC}	Positive Supply Voltage

TRUTH TABLE

INPUTS			OUTPUT	FUNCTION
$\overline{CLEAR}$	D	CLOCK	Q	
L	X	X	L	CLEAR
H	L	⌐	L	
H	H	⌐	H	
H	X	¬	Q_n	NO CHANGE

X : Don't Care

LOGIC DIAGRAM



This logic diagram has not be used to estimate propagation delays

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	-0.5 to +7	V
V_I	DC Input Voltage	-0.5 to V_{CC} + 0.5	V
V_O	DC Output Voltage	-0.5 to V_{CC} + 0.5	V
I_{IK}	DC Input Diode Current	± 20	mA
I_{OK}	DC Output Diode Current	± 20	mA
I_O	DC Output Current	± 50	mA
I_{CC} or I_{GND}	DC V_{CC} or Ground Current	± 400	mA
T_{stg}	Storage Temperature	-65 to +150	°C
T_L	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage (note 1)	2 to 3.6	V
V_I	Input Voltage	0 to V_{CC}	V
V_O	Output Voltage	0 to V_{CC}	V
T_{op}	Operating Temperature	-55 to 125	°C
dt/dv	Input Rise and Fall Time V_{CC} = 3.0V (note 2)	0 to 10	ns/V

1) Truth Table guaranteed: 1.2V to 3.6V
2) V_{IN} from 0.8V to 2V

DC SPECIFICATIONS

Symbol	Parameter	Test Condition		Value							Unit
		V_{CC} (V)		T_A = 25°C			-40 to 85°C		-55 to 125°C		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
V_{IH}	High Level Input Voltage	3.0 to 3.6		2.0			2.0		2.0		V
V_{IL}	Low Level Input Voltage					0.8		0.8		0.8	V
V_{OH}	High Level Output Voltage	3.0	I_O=-50 µA	2.9	2.99		2.9		2.9		V
			I_O=-12 mA	2.58			2.48		2.48		
			I_O=-24 mA				2.2		2.2		
V_{OL}	Low Level Output Voltage	3.0	I_O=50 µA		0.002	0.1		0.1		0.1	V
			I_O=12 mA		0	0.36		0.44		0.44	
			I_O=24 mA					0.55		0.55	
I_I	Input Leakage Current	3.6	V_I = V_{CC} or GND			± 0.1		± 1		± 1	µA
I_{CC}	Quiescent Supply Current	3.6	V_I = V_{CC} or GND			4		40		40	µA
I_{OLD}	Dynamic Output Current (note 1, 2)	3.6	V_{OLD} = 0.8 V max				36		36		mA
I_{OHD}			V_{OHD} = 2 V min				-25		-25		mA

1) Maximum test duration 2ms, one output loaded at time
2) Incident wave switching is guaranteed on transmission lines with impedances as low as 75Ω

DYNAMIC SWITCHING CHARACTERISTICS

Symbol	Parameter	Test Condition		Value							Unit
		V_{CC} (V)		T_A = 25°C			-40 to 85°C		-55 to 125°C		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
V_{OLP}	Dynamic Low Voltage Quiet Output (note 1, 2)	3.3	C_L = 50 pF		0.4	0.8					V
V_{OLV}				-0.8	-0.5						
V_{IHD}	Dynamic High Voltage Input (note 1, 3)	3.3		2							V
V_{ILD}	Dynamic Low Voltage Input (note 1, 3)	3.3				0.8					V

1) Worst case package.
2) Max number of outputs defined as (n). Data inputs are driven 0V to 3.3V, (n-1) outputs switching and one output at GND.
3) Max number of data inputs (n) switching. (n-1) switching 0V to 3.3V. Inputs under test switching: 3.3V to threshold (V_{ILD}), 0V to threshold (V_{IHD}), f=1MHz.

AC ELECTRICAL CHARACTERISTICS (C_L = 50 pF, R_L = 500 Ω, Input $t_r = t_f$ = 3ns)

Symbol	Parameter	Test Condition		Value							Unit
		V_{CC} (V)		T_A = 25°C			-40 to 85°C		-55 to 125°C		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
t_{PLH} t_{PHL}	Propagation Delay Time CK to Q	2.7			7.3	12.0		14.0		16.0	ns
		3.3(*)			6.0	9.0		10.5		12.0	
t_{PHL}	Propagation Delay Time $\overline{CLR}$ to Q	2.7			9.8	15.5		18.0		21.0	ns
		3.3(*)			8.6	12.5		14.5		16.5	
t_W	$\overline{CLEAR}$ Pulse Width	2.7		5.0	2.5		5.0		5.0		ns
		3.3(*)		4.0	2.2		4.0		4.0		
t_W	CLOCK Pulse Width	2.7		5.0	2.0		5.0		5.0		ns
		3.3(*)		4.0	1.6		4.0		4.0		
t_s	Setup Time D to CK, HIGH or LOW	2.7		4.0	-0.4		4.0		5.0		ns
		3.3(*)		3.0	-0.3		3.0		4.0		
t_h	Hold Time D to CK, HIGH or LOW	2.7		3.0	0.4		3.0		3.5		ns
		3.3(*)		2.0	0.3		2.0		2.5		
t_{REM}	Recovery Time $\overline{CLEAR}$ to CLOCK	2.7		4.0	-0.1		4.0		4.5		ns
		3.3(*)		3.0	0.0		3.0		3.5		
f_{MAX}	Maximum Clock Frequency	2.7		60	150		50		50		MHz
		3.3(*)		90	190		70		70		
t_{OSLH} t_{OSHL}	Output To Output Skew Time (note1, 2)	2.7			0.5	1.0		1.0		1.0	ns
		3.3(*)			0.5	1.0		1.0		1.0	

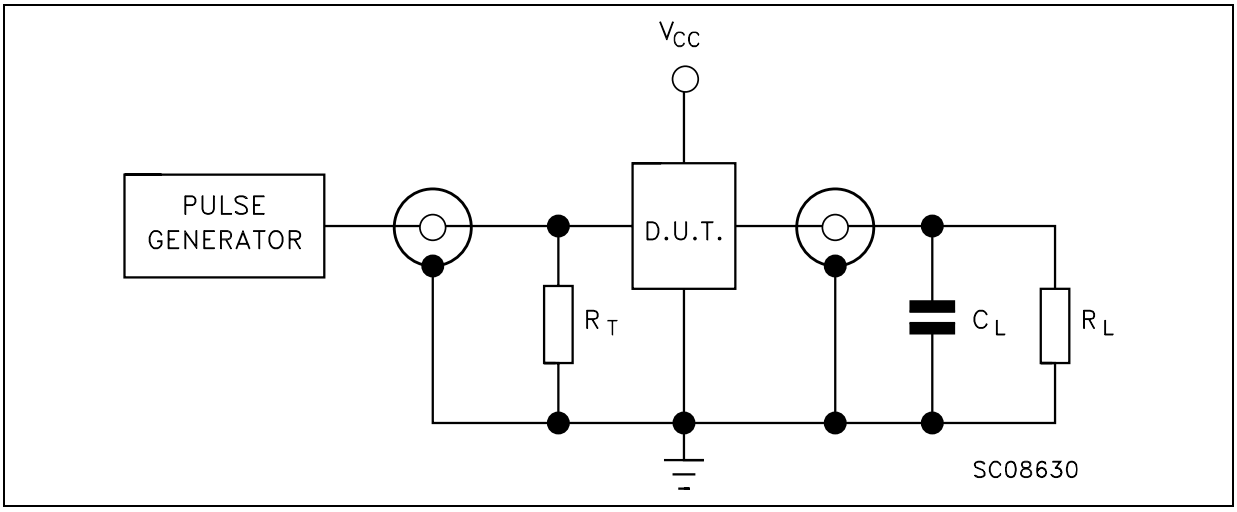
1) Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs of the same device switching in the same direction, either HIGH or LOW ($t_{OSLH} = |t_{PLHm} - t_{PLHn}|$, $t_{OSHL} = |t_{PHLm} - t_{PHLn}|$)
2) Parameter guaranteed by design
(*) Voltage range is 3.3V ± 0.3V

CAPACITIVE CHARACTERISTICS

Symbol	Parameter	Test Condition		Value							Unit
		V_{CC} (V)		T_A = 25°C			-40 to 85°C		-55 to 125°C		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
C_{IN}	Input Capacitance	3.3			5						pF
C_{PD}	Power Dissipation Capacitance (note 1)	3.3	f_{IN} = 10MHz		30						pF

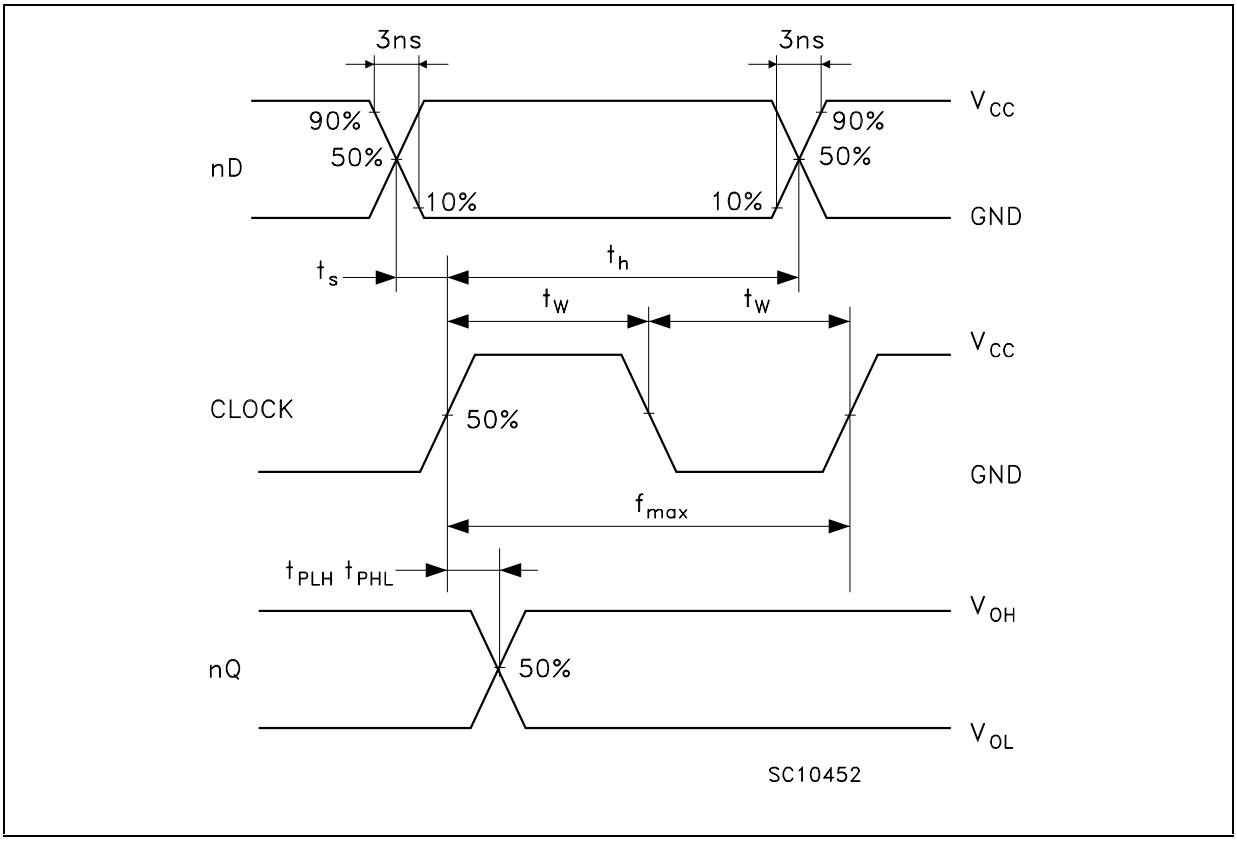
1) C_{PD} is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation. $I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/8$ (per Flip Flop)

TEST CIRCUIT

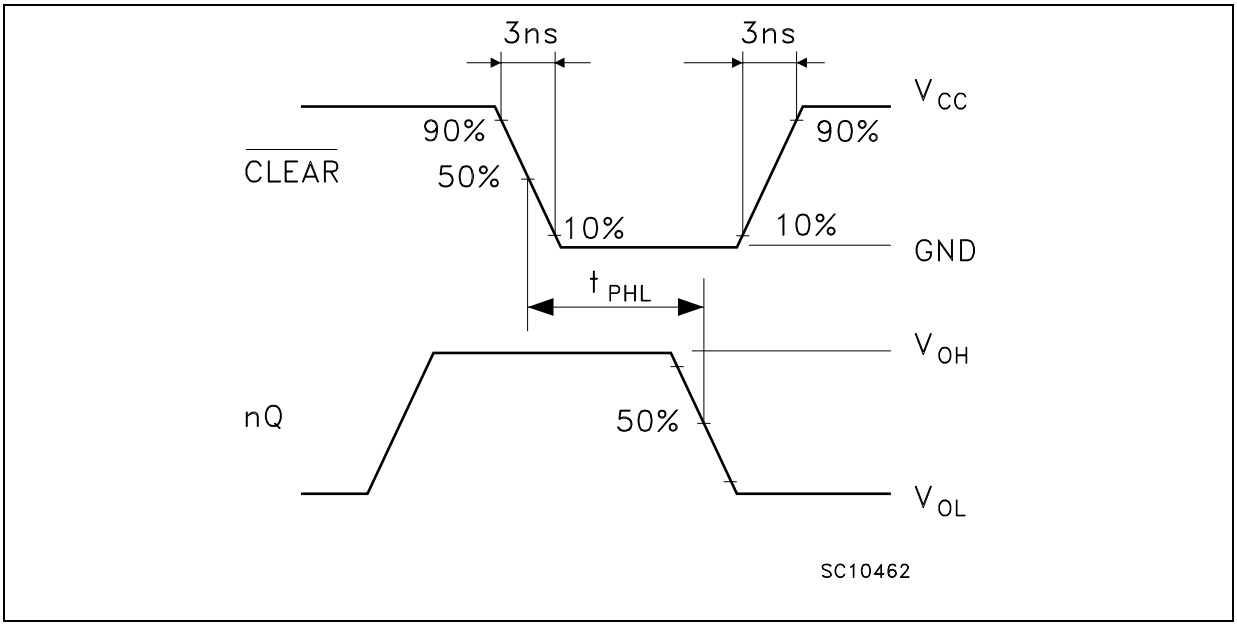


C_L = 50pF or equivalent (includes jig and probe capacitance)
R_L = 500Ω or equivalent
R_T = Z_{OUT} of pulse generator (typically 50Ω)

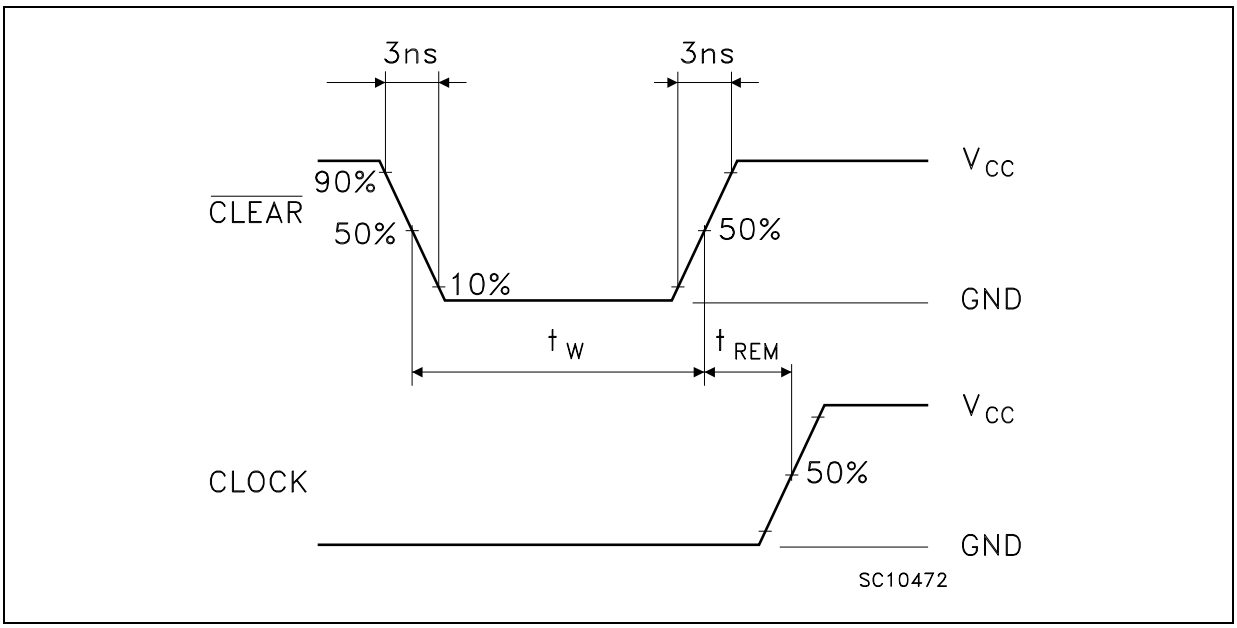
WAVEFORM 1 : PROPAGATION DELAYS, SETUP AND HOLD TIMES CLOCK PULSE WIDTH
(f=1MHz; 50% duty cycle)



WAVEFORM 2: PROPAGATION DELAYS (f=1MHz; 50% duty cycle)

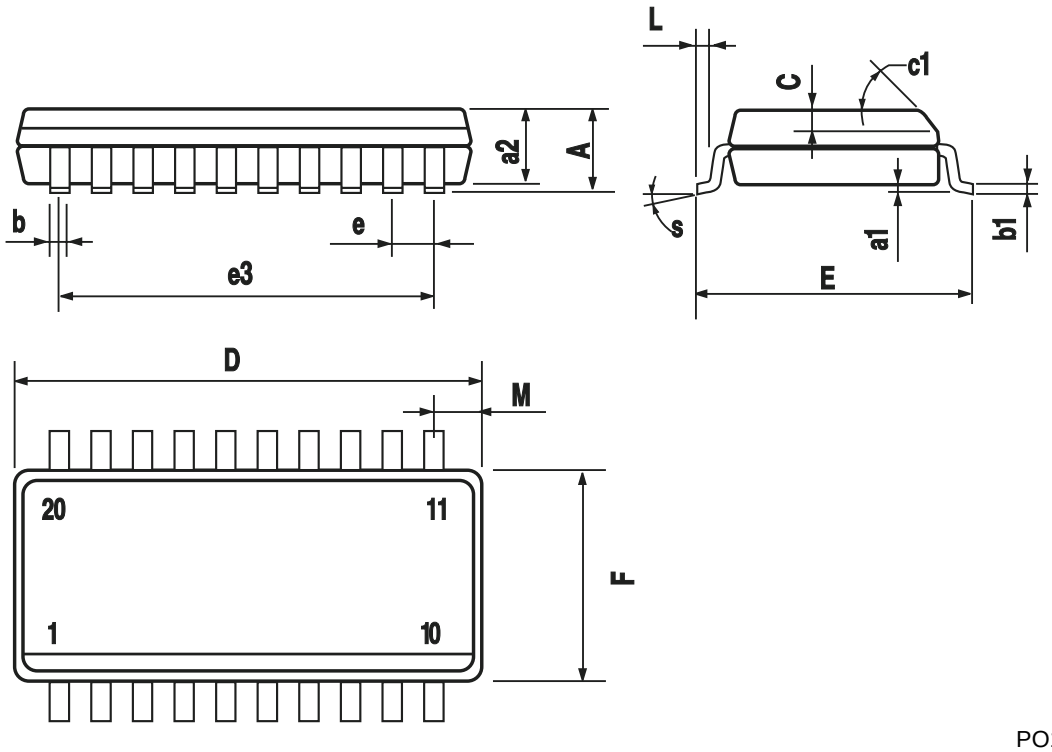


WAVEFORM 3: RECOVERY TIME , CLEAR PULSE WIDTH (f=1MHz; 50% duty cycle)



SO-20 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A			2.65			0.104
a1	0.1		0.2	0.004		0.008
a2			2.45			0.096
b	0.35		0.49	0.014		0.019
b1	0.23		0.32	0.009		0.012
C		0.5			0.020	
c1	45° (typ.)					
D	12.60		13.00	0.496		0.512
E	10.00		10.65	0.393		0.419
e		1.27			0.050	
e3		11.43			0.450	
F	7.40		7.60	0.291		0.300
L	0.50		1.27	0.020		0.050
M			0.75			0.029
S	8° (max.)					



PO13L

TSSOP20 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A			1.2			0.047
A1	0.05		0.15	0.002	0.004	0.006
A2	0.8	1	1.05	0.031	0.039	0.041
b	0.19		0.30	0.007		0.012
c	0.09		0.20	0.004		0.0089
D	6.4	6.5	6.6	0.252	0.256	0.260
E	6.2	6.4	6.6	0.244	0.252	0.260
E1	4.3	4.4	4.48	0.169	0.173	0.176
e		0.65 BSC			0.0256 BSC	
K	0°		8°	0°		8°
L	0.45	0.60	0.75	0.018	0.024	0.030